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### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

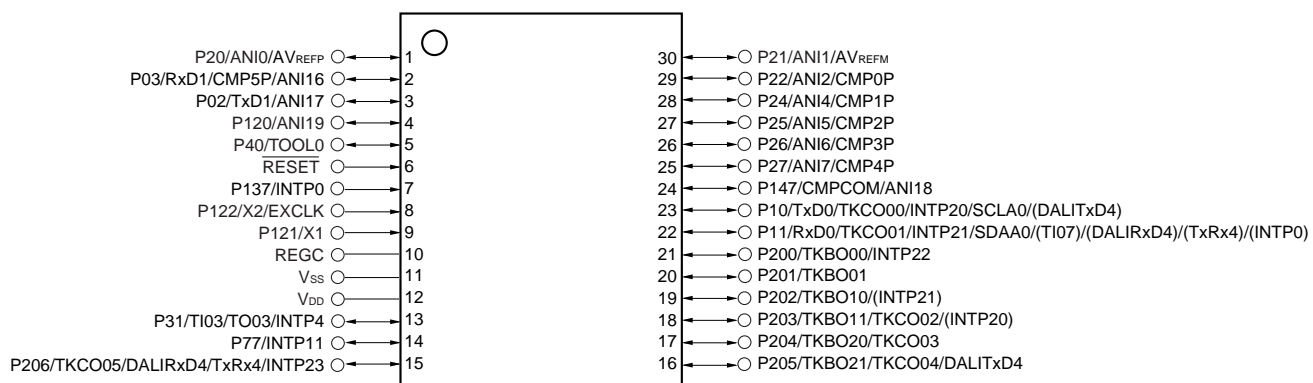
### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Active
Core Processor	RL78
Core Size	16-Bit
Speed	32MHz
Connectivity	I <sup>2</sup> C, LINbus, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	29
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 11x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	38-SSOP (0.240", 6.10mm Width)
Supplier Device Package	38-SSOP
Purchase URL	<a href="https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f107demsp-v0">https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f107demsp-v0</a>

## 1.3.2 30-pin products

- 30-pin plastic LSSOP (7.62 mm (300))



**Caution** Connect the REGC pin to V<sub>SS</sub> via a capacitor (0.47 to 1  $\mu$ F).

**Remarks 1.** For pin identification, see 1.4 Pin Identification.

- 2.** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR1) or the input switch control register (ISC). See **Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR1)** and **Figure 15-20 Format of Input Switch Control Register (ISC)** in the RL78/I1A User's Manual.

**Absolute Maximum Ratings ( $T_A = 25^{\circ}\text{C}$ ) (2/2)**

Parameter	Symbols	Conditions		Ratings	Unit
Output current, high	I <sub>OH1</sub>	Per pin	P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	−40	mA
		Total of all pins −170 mA	P02, P03, P40, P120	−70	mA
			P05, P06, P10 to P12, P30, P31, P75 to P77, P147, P200 to P206	−100	mA
	I <sub>OH2</sub>	Per pin	P20 to P22, P24 to P27	−0.5	mA
		Total of all pins		−2	mA
	Output current, low	I <sub>OL1</sub>	Per pin	P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	40
Total of all pins 170 mA			P02, P03, P40, P120	70	mA
			P05, P06, P10 to P12, P30, P31, P75 to P77, P147, P200 to P206	100	mA
I <sub>OL2</sub>		Per pin	P20 to P22, P24 to P27	1	mA
		Total of all pins		5	mA
Operating ambient temperature		T <sub>A</sub>	In normal operation mode		−40 to +105
	In flash memory programming mode				
Storage temperature	T <sub>stg</sub>			−65 to +150	°C

**Caution** Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

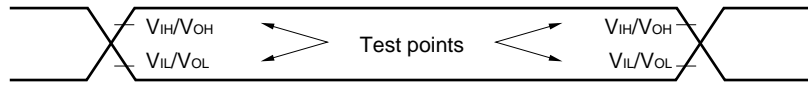
**Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

- Notes**
1. Total current flowing into  $V_{DD}$ , including the input leakage current flowing when the level of the input pin is fixed to  $V_{DD}$  or  $V_{SS}$ . The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, comparator, programmable gain amplifier, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
  2. When high-speed on-chip oscillator and subsystem clock are stopped.
  3. When high-speed system clock and subsystem clock are stopped.
  4. When high-speed on-chip oscillator and high-speed system clock are stopped. When AMPHS1 = 1 (Ultra-low power consumption oscillation). However, not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.
  5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.  
HS (high-speed main) mode:  $2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}@1\text{ MHz to }32\text{ MHz}$   
LS (low-speed main) mode:  $2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}@1\text{ MHz to }8\text{ MHz}$

- Remarks**
1.  $f_{MX}$ : High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  2.  $f_{IH}$ : High-speed on-chip oscillator clock frequency
  3.  $f_{SUB}$ : Subsystem clock frequency (XT1 clock oscillation frequency)
  4. Except subsystem clock operation, temperature condition of the TYP. value is  $T_A = 25^{\circ}\text{C}$

## 2.5 Peripheral Functions Characteristics

### AC Timing Test Points



#### 2.5.1 Serial array unit 0, 4 (UART0, UART1, CSI00, DALI/UART4)

##### (1) During communication at same potential (UART mode)

( $T_A = -40$  to  $+105^\circ\text{C}$ ,  $2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ ,  $V_{SS} = 0\text{ V}$ )

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
Transfer rate <sup>Note 1</sup>		$2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}$		$f_{MCK}/6$		$f_{MCK}/6$	bps
		Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ <sup>Note 2</sup>		5.3		1.3	Mbps

**Notes 1.** Transfer rate in the SNOOZE mode is 4800 bps only.

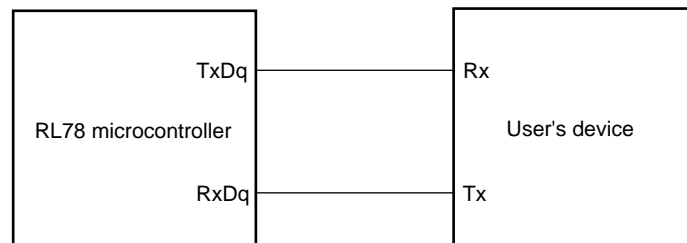
**2.** The maximum operating frequencies of the CPU/peripheral hardware clock ( $f_{CLK}$ ) are:

HS (high-speed main) mode: 32 MHz ( $2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ )

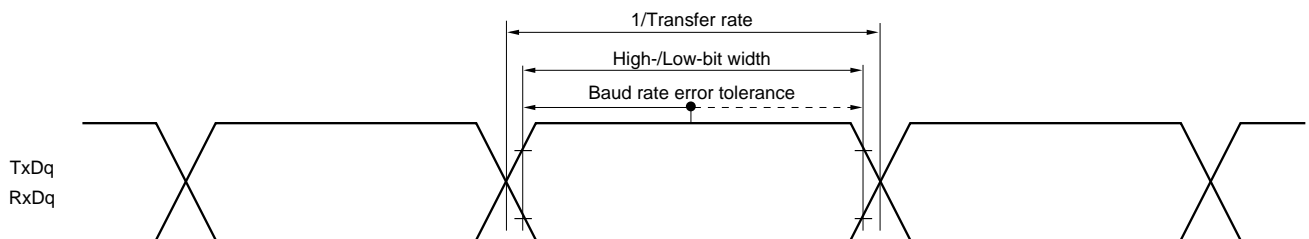
LS (low-speed main) mode: 8 MHz ( $2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ ),  $T_A = -40$  to  $+85^\circ\text{C}$

**Caution** Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

#### UART mode connection diagram (during communication at same potential)



#### UART mode bit width (during communication at same potential) (reference)



**Caution** Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

**Remarks 1.** q: UART number (q = 0, 1), g: PIM and POM number (g = 0, 1)

**2.**  $f_{MCK}$ : Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,

n: Channel number (mn = 00 to 03))

**(5) Communication at different potential (2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output)**  
**( $T_A = -40$  to  $+105^\circ\text{C}$  <sup>Note 3</sup>,  $2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ ,  $V_{SS} = 0\text{ V}$ )**

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	$t_{KCY1}$	$t_{KCY1} \geq 2/f_{CLK}$ $4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$	200		1150		ns
		$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$	300		1150		ns
SCKp high-level width	$t_{KH1}$	$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$	$t_{KCY1}/2 - 50$		$t_{KCY1}/2 - 75$		ns
		$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$	$t_{KCY1}/2 - 120$		$t_{KCY1}/2 - 170$		ns
SCKp low-level width	$t_{KL1}$	$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$	$t_{KCY1}/2 - 7$		$t_{KCY1}/2 - 50$		ns
		$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$	$t_{KCY1}/2 - 10$		$t_{KCY1}/2 - 50$		ns
Slp setup time (to SCKp $\uparrow$ ) <sup>Note 1</sup>	$t_{SIK1}$	$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$	81		479		ns
		$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$	177		479		ns
Slp hold time (from SCKp $\uparrow$ ) <sup>Note 1</sup>	$t_{KSI1}$	$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$	10		19		ns
		$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$	10		19		ns
Delay time from SCKp $\downarrow$ to SOp output <sup>Note 1</sup>	$t_{KSO1}$	$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$		60		100	ns
		$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$		130		195	ns
Slp setup time (to SCKp $\downarrow$ ) <sup>Note 2</sup>	$t_{SIK1}$	$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$	44		110		ns
		$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$	44		110		ns
Slp hold time (from SCKp $\downarrow$ ) <sup>Note 2</sup>	$t_{KSI1}$	$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$	10		19		ns
		$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$	10		19		ns
Delay time from SCKp $\uparrow$ to SOp output <sup>Note 2</sup>	$t_{KSO1}$	$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$		10		25	ns
		$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$		10		25	ns

- Notes**
1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
  2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  3. Operating conditions of LS (low-speed main) mode is  $T_A = -40$  to  $+85^\circ\text{C}$ .

**Caution** Select the TTL input buffer for the Slp pin and the N-ch open drain output ( $V_{DD}$  tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For  $V_{IH}$  and  $V_{IL}$ , see the DC characteristics with TTL input buffer selected.

- Remarks**
1.  $R_b[\Omega]$ : Communication line (SCKp, SOp) pull-up resistance,  $C_b[\text{F}]$ : Communication line (SCKp, SOp) load capacitance,  $V_b[\text{V}]$ : Communication line voltage
  2. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0),  
g: PIM and POM number (g = 1)

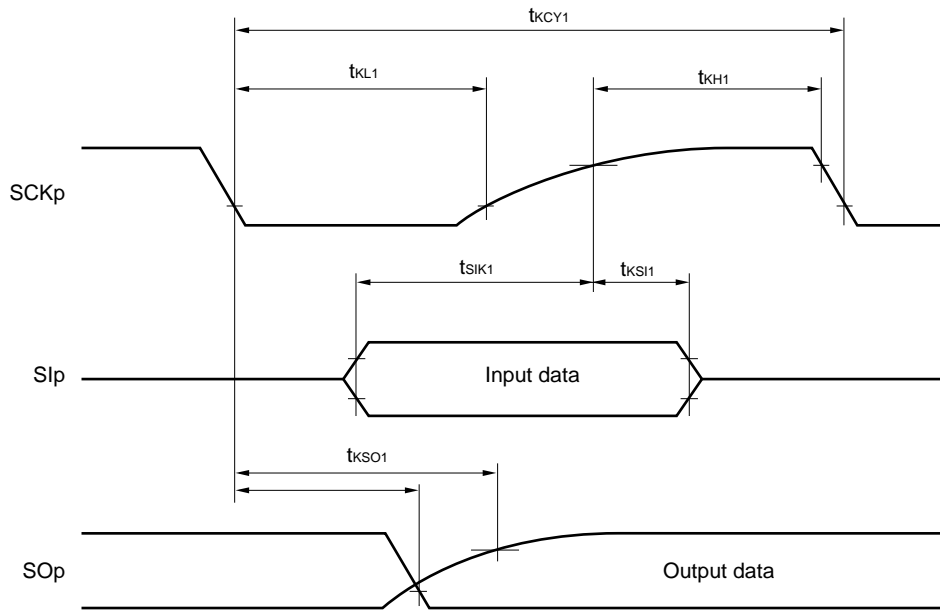
**(6) Communication at different potential (2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output)**  
**( $T_A = -40$  to  $+105^{\circ}\text{C}$  <sup>Note 3</sup>,  $2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ ,  $V_{SS} = 0\text{ V}$ )**

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	$t_{KCY1}$	$t_{KCY1} \geq 4/f_{CLK}$	$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$	300		1150		ns
			$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$	500		1150		ns
SCKp high-level width	$t_{KH1}$		$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$	$t_{KCY1}/2 - 75$		$t_{KCY1}/2 - 75$		ns
			$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$	$t_{KCY1}/2 - 170$		$t_{KCY1}/2 - 170$		ns
SCKp low-level width	$t_{KL1}$		$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$	$t_{KCY1}/2 - 12$		$t_{KCY1}/2 - 50$		ns
			$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$	$t_{KCY1}/2 - 18$		$t_{KCY1}/2 - 50$		ns
Slp setup time (to SCKp $\uparrow$ ) <sup>Note 1</sup>	$t_{SIK1}$		$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$	81		479		ns
			$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$	177		479		ns
Slp hold time (from SCKp $\uparrow$ ) <sup>Note 1</sup>	$t_{SH1}$		$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$	19		19		ns
			$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$	19		19		ns
Delay time from SCKp $\downarrow$ to SOP output <sup>Note 1</sup>	$t_{SO1}$		$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$		100		100	ns
			$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$		195		195	ns
Slp setup time (to SCKp $\downarrow$ ) <sup>Note 2</sup>	$t_{SIK1}$		$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$	44		110		ns
			$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$	44		110		ns
Slp hold time (from SCKp $\downarrow$ ) <sup>Note 2</sup>	$t_{SH1}$		$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$	19		19		ns
			$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$	19		19		ns
Delay time from SCKp $\uparrow$ to SOP output <sup>Note 2</sup>	$t_{SO1}$		$4.0\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ , $2.7\text{ V} \leq V_b \leq 4.0\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 1.4\text{ k}\Omega$		25		25	ns
			$2.7\text{ V} \leq V_{DD} < 4.0\text{ V}$ , $2.3\text{ V} \leq V_b \leq 2.7\text{ V}$ , $C_b = 30\text{ pF}$ , $R_b = 2.7\text{ k}\Omega$		25		25	ns

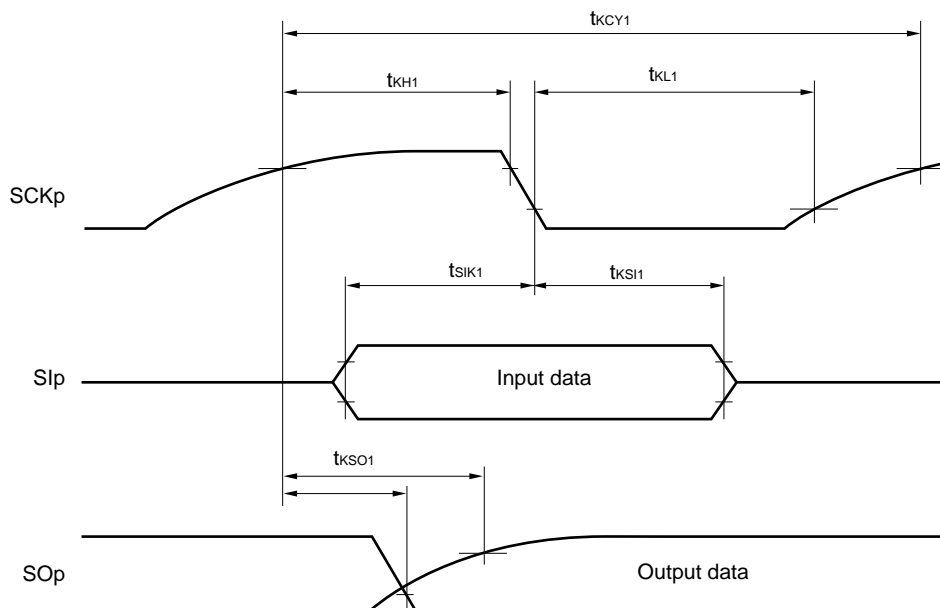
- Notes**
1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
  2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  3. Operating conditions of LS (low-speed main) mode is  $T_A = -40$  to  $+85^{\circ}\text{C}$ .

(Caution and Remarks are listed on the next page.)

**CSI mode serial transfer timing (master mode) (during communication at different potential)**  
**(When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)**



**CSI mode serial transfer timing (master mode) (during communication at different potential)**  
**(When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)**



**Caution** Select the TTL input buffer for the SIp pin and the N-ch open drain output ( $V_{DD}$  tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

**Remark** p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 1)

## 2.6.2 Temperature sensor/internal reference voltage characteristics

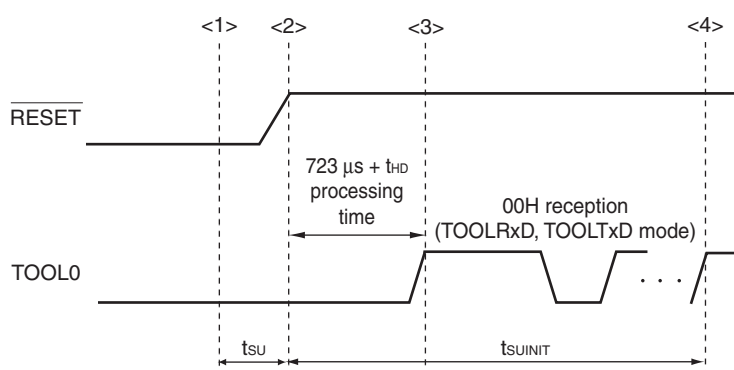
**( $T_A = -40$  to  $+105^\circ\text{C}$ ,  $2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ ,  $V_{SS} = 0\text{ V}$ , HS (high-speed main) mode)**

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	$V_{\text{TMPS25}}$	Setting ADS register = 80H, $T_A = +25^\circ\text{C}$		1.05		V
Internal reference voltage	$V_{\text{BGRT}}$	Setting ADS register = 81H	1.38	1.45	1.5	V
Temperature coefficient	$F_{\text{VTMPS}}$	Temperature sensor that depends on the temperature		-3.6		mV/C
Operation stabilization wait time	$t_{\text{AMP}}$		5			$\mu\text{s}$

## 2.10 Timing of Entry to Flash Memory Programming Modes

**( $T_A = -40$  to  $+105^\circ\text{C}$ ,  $2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ ,  $V_{SS} = 0\text{ V}$ )**

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
How long from when an external reset ends until the initial communication settings are specified	$t_{\text{SUINIT}}$	POR and LVD reset must end before the external reset ends.			100	ms
How long from when the TOOL0 pin is placed at the low level until an external reset ends	$t_{\text{SU}}$	POR and LVD reset must end before the external reset ends.	10			$\mu\text{s}$
How long the TOOL0 pin must be kept at the low level after a reset ends (except soft processing time)	$t_{\text{HD}}$	POR and LVD reset must end before the external reset ends.	1			ms



- <1> The low level is input to the TOOL0 pin.
- <2> The external reset ends (POR and LVD reset must end before the pin reset ends.).
- <3> The TOOL0 pin is set to the high level.
- <4> Complete the baud rate setting by UART reception.

**Remark**  $t_{\text{SUINIT}}$ : The segment shows that it is necessary to finish specifying the initial communication settings within 100 ms from when the resets end.

$t_{\text{SU}}$ : How long from when the TOOL0 pin is placed at the low level until an external reset ends

$t_{\text{HD}}$ : How long to keep the TOOL0 pin at the low level from when the external and internal resets end (except soft processing time)

## 3.2 Oscillator Characteristics

### 3.2.1 X1, XT1 oscillator characteristics

( $T_A = -40$  to  $+125^\circ\text{C}$ ,  $2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ ,  $V_{SS} = 0\text{ V}$ )

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock frequency ( $f_x$ ) <sup>Note</sup>	Ceramic resonator/ crystal resonator		1.0		20.0	MHz
XT1 clock frequency ( $f_{XT}$ ) <sup>Note</sup>	Crystal resonator		32	32.768	35	kHz

**Note** Indicates only permissible oscillator frequency ranges. See **AC Characteristics** for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.

**Caution** Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

**Remark** When using the X1 oscillator and XT1 oscillator, see 5.4 System Clock Oscillator in the RL78/I1A User's Manual.

- Notes**
1. Total current flowing into  $V_{DD}$ , including the input leakage current flowing when the level of the input pin is fixed to  $V_{DD}$  or  $V_{SS}$ . The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, comparator, programmable gain amplifier, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
  2. During HALT instruction execution by flash memory.
  3. When high-speed on-chip oscillator and subsystem clock are stopped.
  4. When high-speed system clock and subsystem clock are stopped.
  5. When high-speed on-chip oscillator and high-speed system clock are stopped. When  $RTCLPC = 1$  and setting ultra-low current consumption ( $AMPHS1 = 1$ ). The current flowing into the RTC is included. However, not including the current flowing into the 12-bit interval timer and watchdog timer.
  6. Not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.
  7. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.  
HS (high-speed main) mode:  $2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}@1\text{ MHz to }20\text{ MHz}$
  8. Regarding the value for current operate the subsystem clock in STOP mode, refer to that in HALT mode.

- Remarks**
1.  $f_{MX}$ : High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  2.  $f_{IH}$ : High-speed on-chip oscillator clock frequency
  3.  $f_{SUB}$ : Subsystem clock frequency (XT1 clock oscillation frequency)
  4. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is  $T_A = 25^{\circ}\text{C}$

**Notes** 1. Current flowing to the  $V_{DD}$ .

2. When the high-speed on-chip oscillator and high-speed system clock are stopped.
3. Current flowing only to the real-time clock (RTC) (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either  $I_{DD1}$  or  $I_{DD2}$ , and  $I_{RTC}$ , when the real-time clock is operating in operating mode or in HALT mode. When the low-speed on-chip oscillator is selected,  $I_{FIL}$  should be added.  $I_{DD2}$  subsystem clock operation includes the operational current of the real-time clock.
4. Current flowing only to the 12-bit interval timer (excluding the operating current of the XT1 oscillator and  $I_{FIL}$  operating current). The current of the RL78 microcontrollers is the sum of the values of either  $I_{DD1}$  or  $I_{DD2}$ , and  $I_{IT}$ , when the 12-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected,  $I_{FIL}$  should be added.
5. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The supply current value of the RL78 microcontrollers is the sum of  $I_{DD1}$ ,  $I_{DD2}$  or  $I_{DD3}$ , and  $I_{WDT}$ , when the watchdog timer is operating.
6. Current flowing only to the A/D converter. The supply current value of the RL78 microcontrollers is the sum of  $I_{DD1}$  or  $I_{DD2}$  and  $I_{ADC}$ , when the A/D converter is operating in operating mode or in HALT mode.
7. Current flowing only to the LVD circuit. The supply current of the RL78 microcontrollers is the sum of  $I_{DD1}$ ,  $I_{DD2}$  or  $I_{DD3}$  and  $I_{LVD}$  when the LVD circuit is in operation.
8. Current flowing during self-programming operation.
9. Current flowing only to the programmable gain amplifier. The supply current value of the RL78 microcontrollers is the sum of  $I_{DD1}$ ,  $I_{DD2}$  or  $I_{DD3}$ , and  $I_{PGA}$ , when the programmable gain amplifier is operating in operating mode or in HALT mode.
10. Current flowing only to the comparator. The supply current value of the RL78 microcontrollers is the sum of  $I_{DD1}$ ,  $I_{DD2}$  or  $I_{DD3}$ , and  $I_{CMP}$ , when the comparator is operating.
11. This is the current required to flow to  $V_{DD}$  pin of the current circuit that is used as the programmable gain amplifier and the comparator.
12. Current flowing only during data flash rewrite.
13. See **21.3.3 SNOOZE mode in the RL78/I1A User's Manual** for shift time to the SNOOZE mode.

**Remarks** 1.  $f_{IL}$ : Low-speed on-chip oscillator clock frequency2.  $f_{SUB}$ : Subsystem clock frequency (XT1 clock oscillation frequency)3.  $f_{CLK}$ : CPU/peripheral hardware clock frequency4. Temperature condition of the TYP. value is  $T_A = 25^\circ\text{C}$ 

5. Example of calculating current value when using programmable gain amplifier and comparator.

Examples 1) TYP. operating current value when three comparator channels, one internal reference voltage generator, and PGA are operating (when  $AV_{REFP} = V_{DD} = 5.0\text{ V}$ )

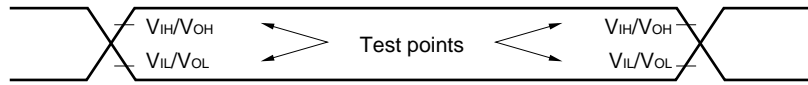
$$\begin{aligned}
 &I_{CMP} \times 3 + I_{VREF} + I_{PGA} + I_{IREF} \\
 &= 41.4\text{ }[\mu\text{A}] \times 3 + 14.8\text{ }[\mu\text{A}] \times 1 + 210\text{ }[\mu\text{A}] + 3.2\text{ }[\mu\text{A}] \\
 &= 352.2\text{ }[\mu\text{A}]
 \end{aligned}$$

Examples 2) TYP. operating current value when using two comparator channels, without using internal reference voltage generator (when  $AV_{REFP} = V_{DD} = 5.0\text{ V}$ )

$$\begin{aligned}
 &I_{CMP} \times 2 + I_{IREF} \\
 &= 41.4\text{ }[\mu\text{A}] \times 2 + 3.2\text{ }[\mu\text{A}] \\
 &= 86.0\text{ }[\mu\text{A}]
 \end{aligned}$$

### 3.5 Peripheral Functions Characteristics

#### AC Timing Test Points



#### 3.5.1 Serial array unit 0, 4 (UART0, UART1, CSI00, DALI/UART4)

##### (1) During communication at same potential (UART mode)

( $T_A = -40$  to  $+125^\circ\text{C}$ ,  $2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ ,  $V_{SS} = 0\text{ V}$ )

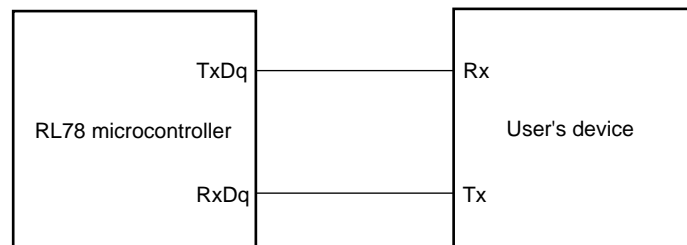
Parameter	Symbol	Conditions	HS (high-speed main) Mode		Unit
			MIN.	MAX.	
Transfer rate <sup>Note 1</sup>				$f_{MCK}/6$	bps
		Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ <sup>Note 2</sup>		3.3	Mbps

**Notes 1.** Transfer rate in the SNOOZE mode is 4800 bps only.

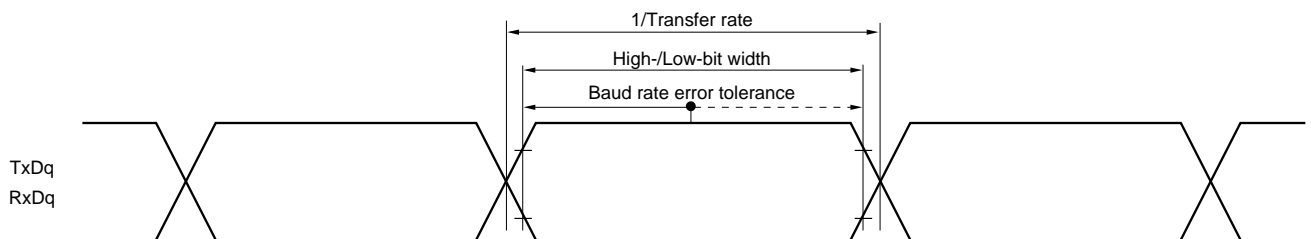
**2.** The operating frequencies of the CPU/peripheral hardware clock ( $f_{CLK}$ ) are:

HS (high-speed main) mode: 20 MHz ( $2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ )

#### UART mode connection diagram (during communication at same potential)



#### UART mode bit width (during communication at same potential) (reference)



**Caution** Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

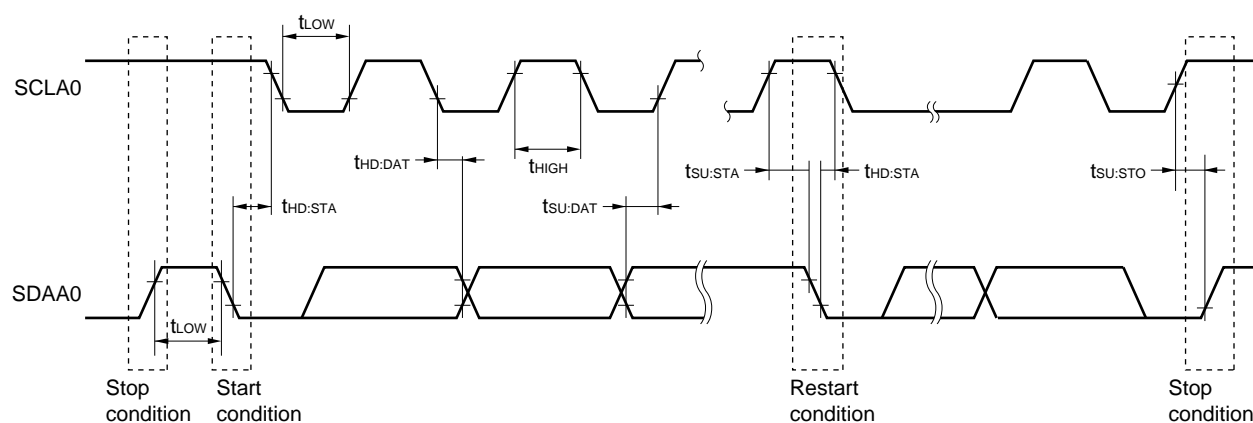
**Remarks 1.** q: UART number (q = 0, 1), g: PIM and POM number (g = 0, 1)

**2.**  $f_{MCK}$ : Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03))

**(2) I<sup>2</sup>C fast mode****( $T_A = -40$  to  $+125^\circ\text{C}$ ,  $2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ ,  $V_{SS} = 0\text{ V}$ )**

Parameter	Symbol	Conditions	HS (high-speed main) Mode		Unit
			MIN.	MAX.	
SCLA0 clock frequency	$f_{SCL}$	fast mode: $f_{CLK} \geq 3.5\text{ MHz}$	0	400	kHz
Setup time of restart condition	$t_{SU:STA}$		0.6		$\mu\text{s}$
Hold time <sup>Note 1</sup>	$t_{HD:STA}$		0.6		$\mu\text{s}$
Hold time when SCLA0 = "L"	$t_{LOW}$		1.3		$\mu\text{s}$
Hold time when SCLA0 = "H"	$t_{HIGH}$		0.6		$\mu\text{s}$
Data setup time (reception)	$t_{SU:DAT}$		100		ns
Data hold time (transmission) <sup>Note 2</sup>	$t_{HD:DAT}$		0	0.9	$\mu\text{s}$
Setup time of stop condition	$t_{SU:STO}$		0.6		$\mu\text{s}$
Bus-free time	$t_{BUF}$		1.3		$\mu\text{s}$

**Notes** 1. The first clock pulse is generated after this period when the start/restart condition is detected.2. The maximum value (MAX.) of  $t_{HD:DAT}$  is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.**Remark** The maximum value of  $C_b$  (communication line capacitance) and the value of  $R_b$  (communication line pull-up resistor) at that time in each mode are as follows.fast mode:  $C_b = 320\text{ pF}$ ,  $R_b = 1.1\text{ k}\Omega$ **I<sup>2</sup>C serial transfer timing**

### 3.6 Analog Characteristics

#### 3.6.1 A/D converter characteristics

Classification of A/D converter characteristics

Input channel	Reference Voltage		
	Reference voltage (+) = $AV_{REFP}$ Reference voltage (–) = $AV_{REFM}$	Reference voltage (+) = $V_{DD}$ Reference voltage (–) = $V_{SS}$	Reference voltage (+) = $V_{BGR}$ Reference voltage (–) = $AV_{REFM}$
ANI0 to ANI2, ANI4 to ANI7	See <b>3.6.1 (1)</b> .	See <b>3.6.1 (3)</b> .	See <b>3.6.1 (4)</b> .
ANI16 to ANI19	See <b>3.6.1 (2)</b> .		
Internal reference voltage Temperature sensor output voltage	See <b>3.6.1 (1)</b> .		–

(2) When reference voltage (+) =  $AV_{REFP}/ANI0$  ( $ADREFP1 = 0$ ,  $ADREFP0 = 1$ ), reference voltage (–) =  $AV_{REFM}/ANI1$  ( $ADREFM = 1$ ), target pin: ANI16 to ANI19

( $T_A = -40$  to  $+125^\circ\text{C}$ ,  $2.7\text{ V} \leq AV_{REFP} \leq V_{DD} \leq 5.5\text{ V}$ ,  $V_{SS} = 0\text{ V}$ , Reference voltage (+) =  $AV_{REFP}$ , Reference voltage (–) =  $AV_{REFM} = 0\text{ V}$ )

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution $AV_{REFP} = V_{DD}$ <sup>Note 3</sup>			1.2	$\pm 5.0$	LSB
Conversion time	$t_{CONV}$	10-bit resolution Target ANI pin : ANI16 to ANI19	$3.6\text{ V} \leq V_{DD} \leq 5.5\text{ V}$	2.125		39	$\mu\text{s}$
			$2.7\text{ V} \leq V_{DD} < 5.5\text{ V}$	3.4		39	$\mu\text{s}$
Zero-scale error <sup>Notes 1, 2</sup>	E <sub>ZS</sub>	10-bit resolution $AV_{REFP} = V_{DD}$ <sup>Note 3</sup>				$\pm 0.35$	%FSR
Full-scale error <sup>Notes 1, 2</sup>	E <sub>FS</sub>	10-bit resolution $AV_{REFP} = V_{DD}$ <sup>Note 3</sup>				$\pm 0.35$	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution $AV_{REFP} = V_{DD}$ <sup>Note 3</sup>				$\pm 3.5$	LSB
Differential linearity error <sup>Note 1</sup>	DLE	10-bit resolution $AV_{REFP} = V_{DD}$ <sup>Note 3</sup>				$\pm 2.0$	LSB
Analog input voltage	V <sub>AIN</sub>	ANI16 to ANI19		0		$AV_{REFP}$ and $V_{DD}$	V

**Notes** 1. Excludes quantization error ( $\pm 1/2$  LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. When  $AV_{REFP} < V_{DD}$ , the MAX. values are as follows.

Overall error: Add  $\pm 4.0$  LSB to the MAX. value when  $AV_{REFP} = V_{DD}$ .

Zero-scale error/Full-scale error: Add  $\pm 0.2\%$ FSR to the MAX. value when  $AV_{REFP} = V_{DD}$ .

Integral linearity error/Differential linearity error: Add  $\pm 2.0$  LSB to the MAX. value when  $AV_{REFP} = V_{DD}$ .

- (3) When reference voltage (+) =  $V_{DD}$  (ADREFP1 = 0, ADREFP0 = 0), reference voltage (–) =  $V_{SS}$  (ADREFM = 0), target pin: ANI0 to ANI2, ANI4 to ANI7, ANI16 to ANI19, internal reference voltage, and temperature sensor output voltage

( $T_A = -40$  to  $+125^\circ\text{C}$ ,  $2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}$ ,  $V_{SS} = 0\text{ V}$ , Reference voltage (+) =  $V_{DD}$ , Reference voltage (–) =  $V_{SS}$ )

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution			1.2	$\pm 7.0$	LSB
Conversion time	$t_{CONV}$	10-bit resolution Target pin: ANI0 to ANI2, ANI4 to ANI7, ANI16 to ANI19	$3.6\text{ V} \leq V_{DD} \leq 5.5\text{ V}$	2.125		39	$\mu\text{s}$
			$2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}$	3.4		39	$\mu\text{s}$
Conversion time	$t_{CONV}$	10-bit resolution Target pin: Internal reference voltage, and temperature sensor output voltage (HS (high-speed main) mode)	$3.6\text{ V} \leq V_{DD} \leq 5.5\text{ V}$	2.375		39	$\mu\text{s}$
			$2.7\text{ V} \leq V_{DD} \leq 5.5\text{ V}$	3.8		39	$\mu\text{s}$
Zero-scale error <sup>Notes 1, 2</sup>	$E_{ZS}$	10-bit resolution				$\pm 0.60$	%FSR
Full-scale error <sup>Notes 1, 2</sup>	$E_{FS}$	10-bit resolution				$\pm 0.60$	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution				$\pm 4.0$	LSB
Differential linearity error <sup>Note 1</sup>	DLE	10-bit resolution				$\pm 2.0$	LSB
Analog input voltage	$V_{AIN}$	ANI0 to ANI2, ANI4 to ANI7		0		$V_{DD}$	V
		ANI16 to ANI19		0		$V_{DD}$	V
		Internal reference voltage (HS (high-speed main) mode)		$V_{BGR}$ <sup>Note 3</sup>			V
		Temperature sensor output voltage (HS (high-speed main) mode)		$V_{TMPS25}$ <sup>Note 3</sup>			V

**Notes** 1. Excludes quantization error ( $\pm 1/2$  LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

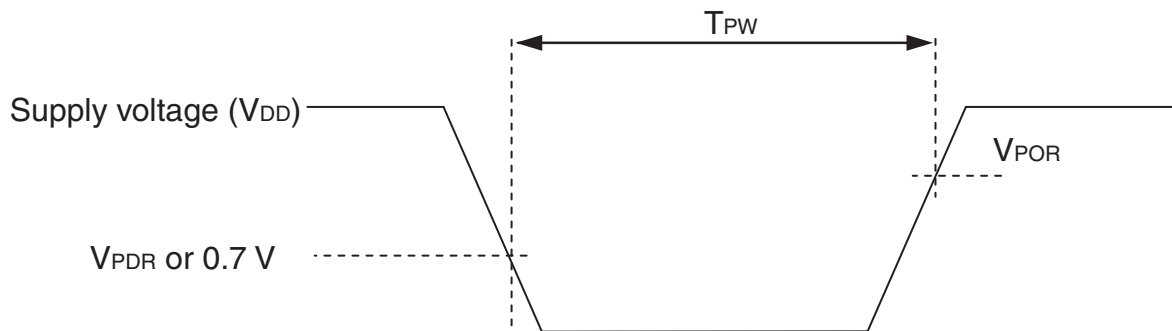
3. See 3.6.2 Temperature sensor/internal reference voltage characteristics.

## 3.6.5 POR circuit characteristics

**( $T_A = -40$  to  $+125^\circ\text{C}$ ,  $V_{SS} = 0$  V)**

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	$V_{POR}$	Power supply rise time	1.45	1.51	1.62	V
	$V_{PDR}$	Power supply fall time	1.44	1.50	1.61	V
Minimum pulse width <sup>Note</sup>	$T_{PW}$		300			$\mu\text{s}$

**Note** Minimum time required for a POR reset when  $V_{DD}$  exceeds below  $V_{PDR}$ . This is also the minimum time required for a POR reset from when  $V_{DD}$  exceeds below 0.7 V to when  $V_{DD}$  exceeds  $V_{POR}$  while STOP mode is entered or the main system clock is stopped through setting bit 0 (HISTOP) and bit 7 (MSTOP) in the clock operation status control register (CSC).



## 3.6.6 LVD circuit characteristics

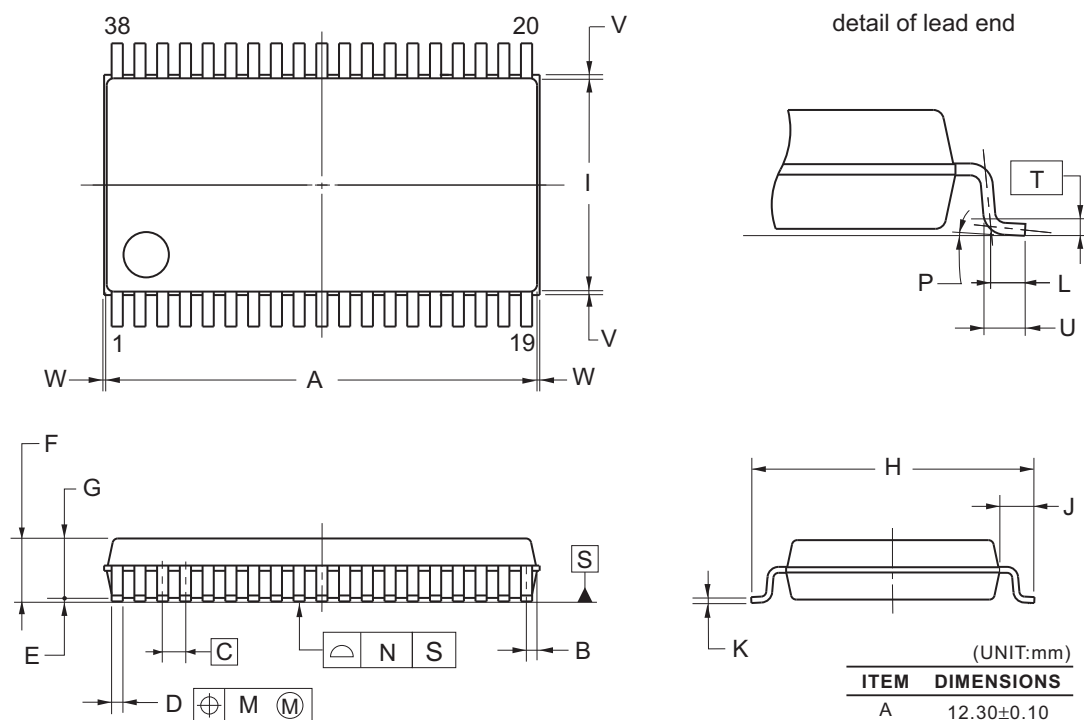
**LVD Detection Voltage of Reset Mode and Interrupt Mode****( $T_A = -40$  to  $+125^\circ\text{C}$ ,  $V_{PDR} \leq V_{DD} \leq 5.5$  V,  $V_{SS} = 0$  V)**

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	$V_{LVD0}$	Power supply rise time	3.97	4.06	4.25	V
		Power supply fall time	3.89	3.98	4.15	V
	$V_{LVD1}$	Power supply rise time	3.67	3.75	3.93	V
		Power supply fall time	3.59	3.67	3.83	V
	$V_{LVD2}$	Power supply rise time	3.06	3.13	3.28	V
		Power supply fall time	2.99	3.06	3.20	V
	$V_{LVD3}$	Power supply rise time	2.95	3.02	3.17	V
		Power supply fall time	2.89	2.96	3.09	V
	$V_{LVD4}$	Power supply rise time	2.85	2.92	3.07	V
		Power supply fall time	2.79	2.86	2.99	V
	$V_{LVD5}$	Power supply rise time	2.75	2.81	2.95	V
		Power supply fall time	2.70	2.75	2.88	V
Minimum pulse width	$t_{LW}$		300			$\mu\text{s}$
Detection delay time					300	$\mu\text{s}$

## 4.3 38-pin Products

R5F107DEGSP#V0, R5F107DEGSP#X0, R5F107DEMSP#V0, R5F107DEMSP#X0

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-SSOP38-0300-0.65	PRSP0038JA-A	P38MC-65-2A4-2	0.3

**NOTE**

Each lead centerline is located within 0.10 mm of its true position (T.P.) at maximum material condition.

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**Renesas Electronics America Inc.**  
2801 Scott Boulevard Santa Clara, CA 95050-2549, U.S.A.  
Tel: +1-408-588-6000, Fax: +1-408-588-6130

**Renesas Electronics Canada Limited**  
9251 Yonge Street, Suite 8309 Richmond Hill, Ontario Canada L4C 9T3  
Tel: +1-905-237-2004

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Dukes Meadow, Millboard Road, Bourne End, Buckinghamshire, SL8 5FH, U.K  
Tel: +44-1628-585-100, Fax: +44-1628-585-900

**Renesas Electronics Europe GmbH**  
Arcadiastrasse 10, 40472 Düsseldorf, Germany  
Tel: +49-211-6503-0, Fax: +49-211-6503-1327

**Renesas Electronics (China) Co., Ltd.**  
Room 1709, Quantum Plaza, No.27 ZhiChunLu Haidian District, Beijing 100191, P.R.China  
Tel: +86-10-8235-1155, Fax: +86-10-8235-7679

**Renesas Electronics (Shanghai) Co., Ltd.**  
Unit 301, Tower A, Central Towers, 555 Langao Road, Putuo District, Shanghai, P. R. China 200333  
Tel: +86-21-2226-0888, Fax: +86-21-2226-0999

**Renesas Electronics Hong Kong Limited**  
Unit 1601-1611, 16/F., Tower 2, Grand Century Place, 193 Prince Edward Road West, Mongkok, Kowloon, Hong Kong  
Tel: +852-2265-6688, Fax: +852 2886-9022

**Renesas Electronics Taiwan Co., Ltd.**  
13F, No. 363, Fu Shing North Road, Taipei 10543, Taiwan  
Tel: +886-2-8175-9600, Fax: +886 2-8175-9670

**Renesas Electronics Singapore Pte. Ltd.**  
80 Bendemeer Road, Unit #06-02 Hyflux Innovation Centre, Singapore 339949  
Tel: +65-6213-0200, Fax: +65-6213-0300

**Renesas Electronics Malaysia Sdn.Bhd.**  
Unit 1207, Block B, Menara Amcorp, Amcorp Trade Centre, No. 18, Jln Persiaran Barat, 46050 Petaling Jaya, Selangor Darul Ehsan, Malaysia  
Tel: +60-3-7955-9390, Fax: +60-3-7955-9510

**Renesas Electronics India Pvt. Ltd.**  
No.777C, 100 Feet Road, HAL II Stage, Indiranagar, Bangalore, India  
Tel: +91-80-67208700, Fax: +91-80-67208777

**Renesas Electronics Korea Co., Ltd.**  
12F., 234 Teheran-ro, Gangnam-Gu, Seoul, 135-080, Korea  
Tel: +82-2-558-3737, Fax: +82-2-558-5141